
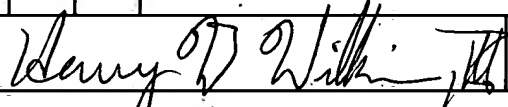
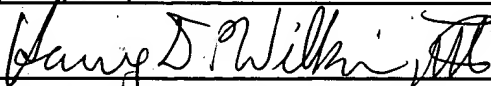




Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5004 DIV2		PRIORITY SERIAL NO. 09/465,492	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vladimir Segal et al.		PRIORITY FILING DATE December 16, 1999	
				PRIORITY GROUP 1742			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
HW	AA	4,619,695	Oikawa et al.	75	65EB		
BW	AB	5,400,633	Segal et al.	72	272		
BW	AC	5,513,512	Segal	72	253.1		
BW	AD	5,590,389	Dunlop et al.	419	67		
BW	AE	5,600,989	Segal et al.	72	253.1		
BW	AF	5,673,581	Setal	72	184		
BW	AG	4,663,120	Parent et al.				
BW	AH	4,762,558	German et al.				
BW	AI	4,889,745	Sata				
BW	AJ	5,330,701	Shaw et al.				
BW	AK	5,418,071	Satou et al.				
BW	AL	5,508,000	Satou et al.				
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	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
BW	AM	590904	EP	C23C	14/34		
BW	AN	9201080	PCT	C23C	14/35		
BW	AO	610107	Japan (*transl. of Abst)	C22	18	X*	
BW	AP	693400	Japan (*transl. of Abst)	C22	18	X*	
BW	AQ	6256919	Japan (*transl. of Abst)	C22	18	X*	
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
HW	AR		C. Klein et al., "Manual of Mineralogy", pp 39-40				
HW	AS		S. Wright et al. "Effect of Annealing Temperature on the Texture of Rolled Tantalum and Tantalum-10 Wt.% Tungsten, reprinted from Tungsten and Refractory Metals 2, pp 501-508				
HW	AT		H-R Wenk, "Preferred Orientation in Deformed Metals and Rocks: An Introduction to Modern Texture Analysis", 1985, pp 8-10				
EXAMINER				DATE CONSIDERED 8/7/02			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							



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U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
HW	AA	5,608,911	03/1997	Shaw et al.				
	AB	5,772,860	06/1998	Sawada et al.				
	AC	5,993,621	11/1999	Liu				
	AD	5,798,005	08/1998	Murata et al.				
	AE	5,282,946	02/1994	Kinoshita et al.				
	AF	5,993,575	11/1999	Lo et al.				
	AG	5,809,393	09/1998	Dunlop et al.				
	AH	5,468,401	11/1995	Lum et al.				
	AI	5,087,297	02/1992	Pouliquen				
	AJ	5,693,203	12/1997	Ohhashi et al.				
HW	AK	5,074,907	12/1991	Amato et al.				
	AL	4,525,417	06/1985	Dimigen et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
HW	AM	8-100255	04/1996	Japan			X	
	AN	8-64554	03/1996	Japan			X	
	AO	06264232	09/1994	Japan			X	
	AP	WO 00/31310	06/2000	PCT				
HW	AQ	7-90566	04/1995	JAPAN			X	
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HW	AR		B.D. Cullity, "Structure of Polycrystalline Aggregates", <u>Elements of X-ray Diffraction</u> , pp 294-297					
	AS							
	AT							
EXAMINER					DATE CONSIDERED			8/7/02
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				PRIORITY FILING DATE December 16, 1999		PRIORITY GROUP 1742	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
HW	AA	SN 09/098,700 As filed and Amended	Shah et al.			6/17/98	
HW	AB	4,842,706	06/1989	Fukasawa et al.			
HW	AC	4,960,163	10/1990	Fang et al.			
HW	AD	5,780,755	07/1998	Dunlop et al.			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
HW	AM	08269701	10/1996	Japan			X
HW	AN	08232061	06/1996	Japan			X
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
HW	AR	B.D. Cullity, "Structure of Polycrystalline Aggregates", <u>Elements of X-ray Diffraction</u> , pp 294-297					
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EXAMINER				DATE CONSIDERED			
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Form PTO 1497		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5004DIV2		SERIAL NO. 09/912,652		
				APPLICANT Segal et al.				
				FILING DATE July 24, 2001		PRIORITY GROUP 1742		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
HW	AA	5,850,755	12/98	Segal				
HW	AB	5,456,815	10/95	Fukuyo et al.				
HW	AC	5,826,456	10/98	Kawazoe et al.				
HW	AD	5,413,650	05/95	Jarrett et al.				
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
HW	AM	882 813	12/98	EPO				
HW	AN	WO 99/66100	12/99	PCT				
HW	AO	WO 87/07650	12/87	PCT				
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
HW	AR		Mukai, T. et al, "Dynamic Mechanical Properties of a Near-Nano Aluminum Alloy Processed by Equal-Channel-Angular-Extrusion",					
			Nano-Structured Materials, Vol. 10, No. 5, pp. 755-765 (1998) Elsevier Science Ltd.					
HW	AS		Hatch, J.E., <u>ALUMINUM</u> , 1984, Chap. 5, "Metallurgy of Heat Treatment and General Principles of Precipitation Hardening", pp. 134-					
			157, 175-183.					
HW	AT		Ferrasse, S. et al., "Development of a Submicrometer-Grained Microstructure in Aluminum 6061 Using Equal Channel Angular					
			Extrusion", J. Mater. Res. Vol. 12, No. 5, May 1997, pp. 1253-1261.					
EXAMINER					DATE CONSIDERED 8/7/02			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								

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Vladimir SegalFILING DATE
July 24, 2001GROUP
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
HW	AA 6,193,821 B1	2/01	Zhang			
HW	AB 6,348,113 B1	2/02	Michaluk et al.			
HW	AC 6,085,966	7/00	Shimomuki et al.			
HW	AD 6,024,852	2/00	Tamura et al.			
HW	AE 5,798,005	08/98	Murata et al.			
HW	AF 5,231,306	07/93	Meikle et al.			
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
HW	AM 08146201	07.06.1996	Japan				
HW	AN 10008244	13.01.1998	Japan				
HW	AO WO 99/27150	03.06.1999	PCT				
HW	AP WO 99/02743	21.01.1999	PCT				
HW	AQ WO 01/29279 A1	26.04.2001	PCT				

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

HW	AR	Ferrasse, S. et al., "Microstructure and Properties of Copper and Aluminum Alloy 3003 Heavily Worked by Equal Channel Angular Extrusion", Metallurgical and Materials Transactions A, vol. 28A, April 1997, pp. 1047-1057.
HW	AS	Pavate et al., "Correlation between Aluminum alloy sputtering target metallurgical characteristics, Arc initiation, and In-film defect density", SPIE Vol. 3214, 1997, pp. 42-47.
	AT	

EXAMINER

Kerry S. Wilk, #116

DATE CONSIDERED

8/7/02

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